

Notice of References Cited	Application/Control No. 10/615,955		Applicant(s)/Patent Under Reexamination ONO ET AL.	
	Examiner John D. Lee <i>John D. Lee</i>		Art Unit 2874	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,617,595	09-2003	Okunuki, Masahiko	250/492.22
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	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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